

NTTFS4H05NTAG-VB Datasheet N-Channel 20-V (D-S) MOSFET

PRODUCT SUMMARY						
V _{DS} (V)	$R_{DS(on)}$ (Ω)	I _D (A) ^{a, e}	Q _g (Typ)			
20	0.0020 at V _{GS} = 4.5 V	100	86 nC			
20	0.0025 at V _{GS} = 2.5 V	95	00 110			

Bottom View

DFN 3X3

Top View

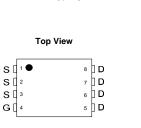
FEATURES

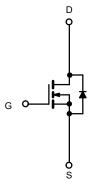
- Trench Power MOSFET
- 100 % R_q and UIS Tested
- Compliant to RoHS Directive 2011/65/EU



APPLICATIONS

- OR-ing
- Server
- DC/DC





N-Channel MOSFET

Parameter	Symbol	Limit	Unit		
Drain-Source Voltage	V _{DS}	20	V		
Gate-Source Voltage		V _{GS}			± 12
	T _C = 25 °C		100 ^{a, e}		
Continuous Drain Current (T _{.I} = 175 °C)	T _C = 70 °C		95 ^e		
Continuous Diam Guirent (1) = 173 C)	T _A = 25 °C	I _D	35.8 ^{b, c}	A	
	T _A = 70 °C		27 ^{b, c}		
Pulsed Drain Current		I _{DM}	300		
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	39		
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	94.8	mJ	
Continuous Source-Drain Diode Current	T _C = 25 °C	L	90 ^{a, e}	^	
Continuous Source-Drain Diode Current	T _A = 25 °C	I _S	3.13 ^{b, c}	A	
	T _C = 25 °C		250 ^a		
Madana Pauca Diadia dia	T _C = 70 °C	P _D	175	w	
Maximum Power Dissipation	T _A = 25 °C	r _D	3.75 ^{b, c}	VV	
	T _A = 70 °C		2.63 ^{b, c}		
Operating Junction and Storage Temperature Range		T _J , T _{stg}	- 55 to 175	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Тур.	Max.	Unit	
Maximum Junction-to-Ambient ^{b, d}	t ≤ 10 sec	R _{thJA}	32	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.5	0.6	- C/vv	

Notes:

- a. Based on $T_C = 25 \,^{\circ}C$.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 10 sec.
- d. Maximum under steady state conditions is 90 °C/W.
- e. Calculated based on maximum junction temperature. Package limitation current is 90 A.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static				'			
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} = 0 V, I _D = 250 μA	20			V	
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	L = 250 uA		35		mV/°C	
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	I _D = 250 μA		- 7.5			
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = 250 \mu A$	0.5		1.0	V	
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA	
Zana Osta Waltana Basin Osmant		V _{DS} = 20 V, V _{GS} = 0 V			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 20 V, V _{GS} = 0 V, T _J = 55 °C			10		
On-State Drain Current ^a	I _{D(on)}	$V_{DS} \ge 5 \text{ V}, V_{GS} = 10 \text{ V}$	90			Α	
		V _{GS} = 10 V,I _D = 38.8 A		0.0020		Ω	
Drain-Source On-State Resistance ^a	R _{DS(on)}	$V_{GS} = 4.5 \text{ V}, I_D = 37 \text{ A}$		0.0025			
Forward Transconductance ^a	9 _{fs}	V _{DS} = 10 V, I _D = 38.8 A		160		S	
Dynamic ^b				'			
Input Capacitance	C _{iss}			6500		pF	
Output Capacitance	C _{oss}	V_{DS} = 10 V, V_{GS} = 0 V, f = 1 MHz		1725			
Reverse Transfer Capacitance	C _{rss}			970			
Tatal Cata Charma	Q_g $V_{DS} = 10 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 38.8 \text{ A}$	V _{DS} = 10 V, V _{GS} = 10 V, I _D = 38.8 A		171	257		
Total Gate Charge			81.5	123	,,,		
Gate-Source Charge	Q _{gs}	V_{DS} = 10 V, V_{GS} = 4.5 V, I_{D} = 28.8 A		34		nC	
Gate-Drain Charge	Q _{gd}			29			
Gate Resistance	R _g	f = 1 MHz		1.4	2.1	Ω	
Turn-On Delay Time	t _{d(on)}			18	27		
Rise Time	t _r	V_{DD} = 10 V, R_L = 0.625 Ω		11	17	-	
Turn-Off Delay Time	t _{d(off)}	$I_D\cong 24$ A, V_{GEN} = 10 V, R_g = 1 Ω		70	105		
Fall Time	t _f			10	15		
Turn-On Delay Time	t _{d(on)}			55	83	ns	
Rise Time	t _r	V_{DD} = 10 V, R_L = 0.67 Ω		180	270		
Turn-Off Delay Time	t _{d(off)}	$I_D\cong$ 22.5 A, V_{GEN} = 4.5 V, R_g = 1 Ω		55	83		
Fall Time	t _f			12	18		
Drain-Source Body Diode Characteristic	s			'			
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			100	۸	
Pulse Diode Forward Current ^a	I _{SM}				300	A	
Body Diode Voltage	V _{SD}	I _S = 22 A		0.8	1.2	V	
Body Diode Reverse Recovery Time	t _{rr}			52	60	ns	
Body Diode Reverse Recovery Charge	Q _{rr}	- - I _F = 20 A, di/dt = 100 A/μs, T _J = 25 °C		70.2	105	nC	
Reverse Recovery Fall Time	t _a	i _F - 20 A, αι/αι - 100 A/μs, 1 _J = 25 C		27			
Reverse Recovery Rise Time	t _b			25		ns	

Notes:

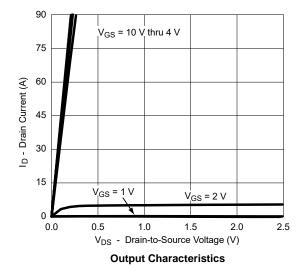
- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

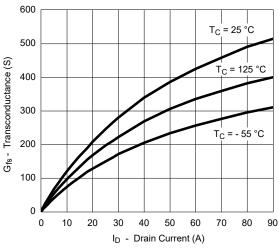
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

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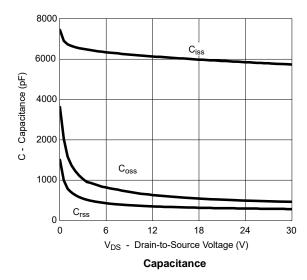


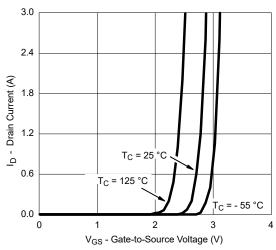
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



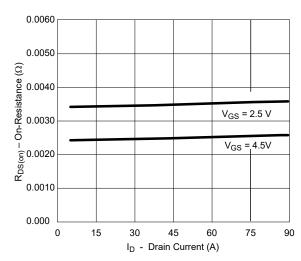


Transconductance

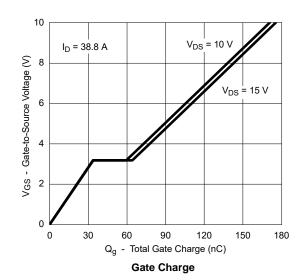




Transfer Characteristics



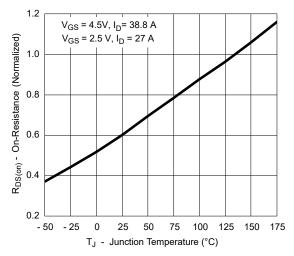
R_{DS(on)} vs. Drain Current



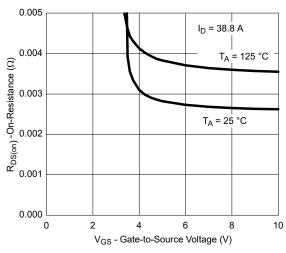
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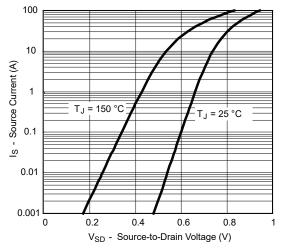
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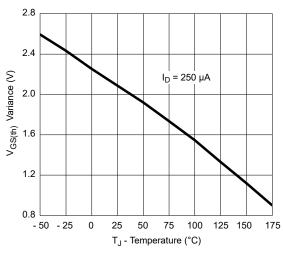
On-Resistance vs. Junction Temperature



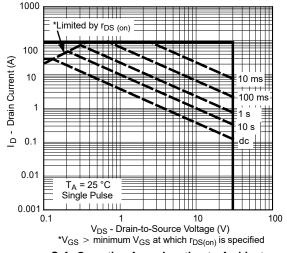
 $R_{DS(on)}$ vs. V_{GS} vs. Temperature



Forward Diode Voltage vs. Temperature



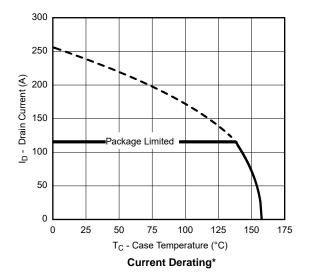
Threshold Voltage

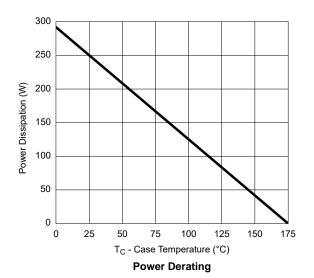


Safe Operating Area, Junction-to-Ambient

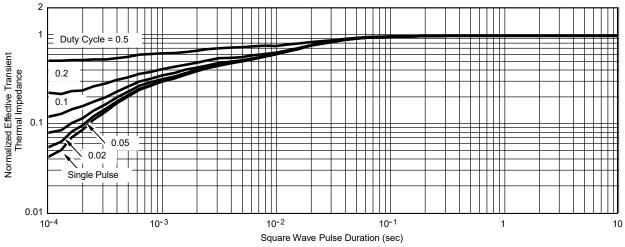


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)





*The power dissipation P_D is based on $T_{J(max)}$ = 175 °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.

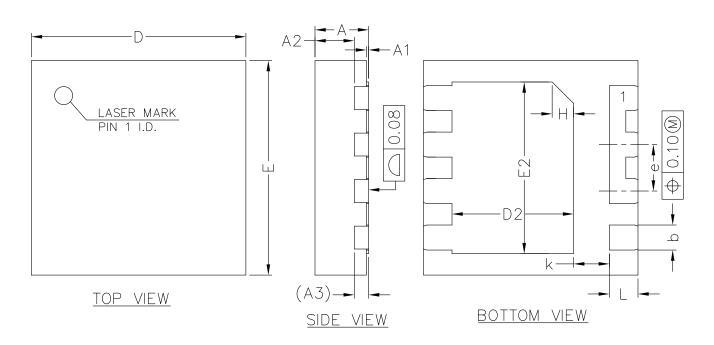


Normalized Thermal Transient Impedance, Junction-to-Case

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DFN 3x3





COMMON DIMENSIONS
(UNITS OF MEASURE=MILLIMETER)

SYMBOL	MIN	NOM	MAX	
Α	0.70	0.75	0.80	
A1	0.00	0.02	0.05	
A2	0.50	0.55	0.60	
А3	0.20REF			
b	0.30	0.35	0.40	
D	2.90	3.00	3.10	
Е	2.90	3.00	3.10	
D2	1.60	1.70	1.80	
E2	2.30	2.40	2.50	
е	0.55	0.65	0.75	
K	0.40	0.50	0.60	
L	0.35	0.40	0.45	

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